



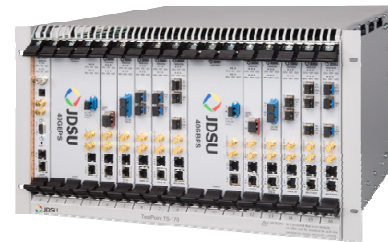
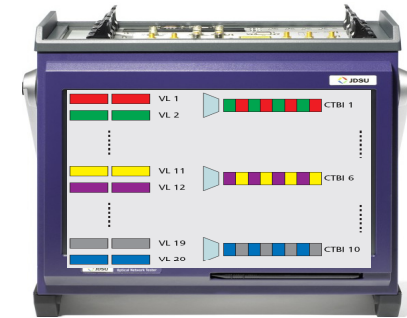
ONT-503/506/512

Optical Network Transport

次世代／旧世代トランスポートネットワーク試験システム

JDSU 40/100GE Test Solutions

- **ONT MLD BERT**
 - Complete 100GE test solution – from physical layer to layer L3 and OTUx
 - Available for demo
- **MAP**
 - Wide range of optical test solutions
- **Hydra (Circadian)**
 - SRS
- **Testpoint**
 - Traffic Generation for Ethernet, FC & transport



New 10Gbps Module - Module-E 機能一覽

Unframed BERT 9.953; 10.000, 10.313, 10.519, 10.664, 10.709 Gb/s
11.049, 11.095, 11.270, 11.318 Gb/s

10GigE WAN

- PHYS 9.95Gb/s
- WIS (SDH/SONET)
- PCS
- MAC
- IPv4/v6
- RFC 2544

10GigE LAN

- PHYS 10.3Gb/s
- PCS
- MAC
- IPv4/v6
- RFC 2544

SDH/SONET

- 9.95Gb/s
- STM-64c/OC-192c
- MultiChannel HO
64xVC-4/192x STS1

Fiber Channel

- 10.5Gb/s
- PCS BERT

OTN 10.7Gb/s

- BULK
- 10GigE WAN
- STM-64c/OC-192c
- OTN-Muxing

OTN 11.05/ 11.1 Gb/s

- BULK
- 10GigE LAN

OTN 11.27/ 11.32Gb/s

- BULK
- FC L1 BERT



Monitoring Through Mode

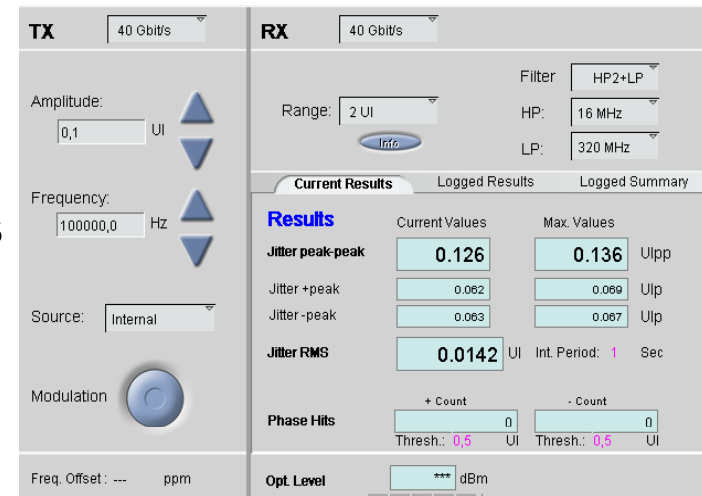
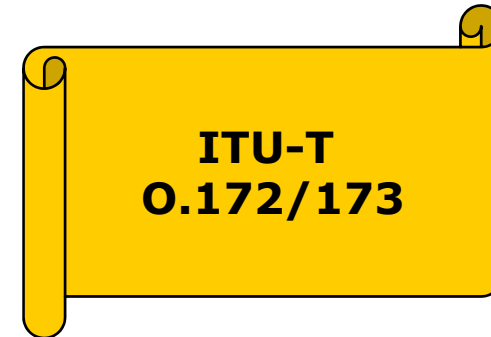
Intrusive Through Mode

Electrical Interfaces (HW option)

Support for Test Automation

40/43G Jitter/Wander + Electrical Testing

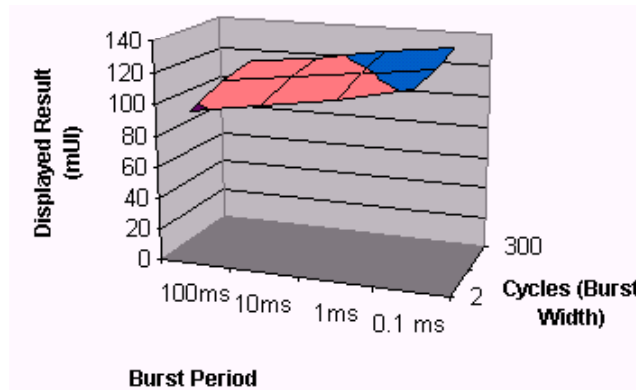
- TX & RX Jitter for 40/43G
 - Testing at electrical and optical interfaces
 - Peak, RMS and Phase Hit measurements
 - Automatic measurement modes:
 - Maximum Tolerable Jitter
 - Fast Maximum Tolerable Jitter
 - Jitter Transfer Function (selective)
- TX & RX Wander at 40/43G
 - TIE measurements with four sample rates
 - MTIE/ TDEV online, frequency offset, drift rate



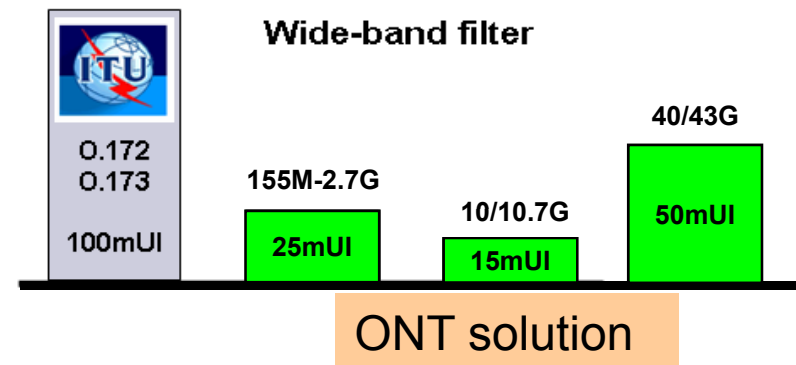
Highest Accuracy Jitter Test Solution

- Testing at both optical and electrical interfaces for SONET/SDH/OTN rates from 155M-43G
- Highest receiver accuracy of 15mUI to qualify state of the art designs and transponders
- Fully compliant to ITU-T O.172 Appendix VII and VIII using in-house Reference Transmitter
- Detects OTN mapping jitter ITU-T G.8251
- Accuracy map available

ITU-T O.172
Appendix VII/VIII



Guaranteed peak-to-peak jitter



Best in class Wander analysis

- Wander analysis at 155M/s to 43G/s with up to 1000 samples/s
- Fully integrated into ONT Platform
- Wander over time
- Automatic Wander mode MTW
- Wander Transfer
- Online MTIE/TDEV analysis
- Separate clock reference input
- Graphical results displayed against ITU-T/ETSI/ANSI/Telcordia standards
- TDEV/white noise generation
- BITS/SETS output

